



# PERRY JOHNSON LABORATORY ACCREDITATION, INC.

## Certificate of Accreditation

*Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:*

***IEC Electronics Analysis & Testing Laboratory (IATL)***  
***1450 Mission Avenue, Albuquerque, NM 87107***

*(Hereinafter called the Organization) and hereby declares that Organization is accredited  
in accordance with the recognized International Standard:*

**ISO/IEC 17025:2005**

This accreditation demonstrates technical competence for a defined scope and the  
operation of a laboratory quality management system  
(as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

***Chemical, Mechanical and Non-Destructive Testing***  
***(As detailed in the supplement)***

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen  
President/Operations Manager

Perry Johnson Laboratory  
Accreditation, Inc. (PJLA)  
755 W. Big Beaver, Suite 1325  
Troy, Michigan 48084

*Initial Accreditation Date:*

August 16, 2018

*Issue Date:*

August 16, 2018

*Expiration Date:*

October 12, 2019

*Accreditation No.:*

102178

*Certificate No.:*

L18-425

*The validity of this certificate is maintained through ongoing assessments based on a  
continuous accreditation cycle. The validity of this certificate should be  
confirmed through the PJLA website: [www.pjilabs.com](http://www.pjilabs.com)*



# Certificate of Accreditation: Supplement

## IEC Electronics Analysis & Testing Laboratory (IATL)

1450 Mission Avenue, Albuquerque, NM 87107  
 Contact Name: John Petty Phone: 505-345-5591

*Accreditation is granted to the facility to perform the following testing:*

FIELD OF TEST	ITEMS, MATERIALS OR PRODUCTS TESTED	SPECIFIC TESTS OR PROPERTIES MEASURED	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED
Chemical <sup>F</sup>	Suspect/Counterfeit EEE Part Detection	Remarking/Resurfacing	SAE AS6171/2
		De-capsulation and Die Verification	SAE AS6171/4 Chemical De-capsulation, Mechanical Disassembly Plasma, Reactive Ion Etching
Mechanical <sup>F</sup>	Polymers, Non-volatile Residue, Material Electrical, Electronic and Electromechanical (EEE) Components	Material Characterization	ASTM E334
		Thermogravimetric Analysis	ASTM E1131
	Suspect/Counterfeit EEE Parts Detection	Thermogravimetric Analysis	SAE AS6171/10
		SEM Examination Internal/External Visual	SAE AS6171/2
		Material Characterization	SAE AS6171/9
	Electrical, Electronic and Electromechanical (EEE) Components	Curve Trace	MIL-STD-883, Method 5003
		Fine Leak Testing Leak Rate	MIL-STD-883, Method 1014
		Gross Leak Testing Examination/Inspection	MIL-STD-750, Method 1071 MIL-STD-202, Method 112
		Exposure/Temperature Cycling	MIL-STD-883, Method 1010 MIL-STD-750, Method 1051
		SEM Examination/Inspection	MIL-STD-750, Method 2077 MIL-STD-883, Method 2018
		Internal Examination/Inspection	MIL-STD-883, Method 2010 and 2013 MIL-STD-750, Method 2072
		Particle Impact Noise Detection (PIND)	MIL-STD-883, Method 2020 MIL-STD-750, Method 2052
		Die Shear Grams and Force	MIL-STD-883, Method 2019 MIL-STD-750, Method 2037
		Wire Pull	MIL-STD-883, Method 2011 MIL-STD-750, Method 2037
	Non-Destructive <sup>F</sup>	Electrical, Electronic and Electromechanical (EEE) Components	Elemental content by XRF, EDS (Lead, tin, etc.)
Elemental thickness XRF (ENIG)			IPC-4552
Radiographic Examination/Inspection			MIL-STD-883, Method 2012 MIL-STD-750, Method 2076 MIL-STD-202, Method 209



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Non-Destructive <sup>F</sup>	Electrical, Electronic and Electromechanical (EEE) Components	Acoustic Microscopy (CSAM) Examination/Inspection	IPC/JEDEC J-STD-035
		Suspect/Counterfeit EEE Part Detection	Elemental content by XRF, EDS
	Suspect/Counterfeit EEE Part Detection	Radiographic Examination/Inspection	SAE AS6171/5
		Acoustic Microscopy (CSAM) Examination/Inspection	SAE AS6171/6

- The presence of a superscript F means that the laboratory performs testing of the indicated parameter at its fixed location. Example: Outside Micrometer<sup>F</sup> would mean that the laboratory performs this testing at its fixed location.

